# Features

- Fast Read Access Time 90 ns
- Word-wide or Byte-wide Configurable
- 4-megabit Flash and Mask ROM Compatible
- Low-power CMOS Operation
  - 100 µA Maximum Standby
  - 50 mA Maximum Active at 5 MHz
- Wide Selection of JEDEC Standard Packages
  - 40-lead 600 mil PDIP
  - 44-lead SOIC (SOP)
  - 48-lead TSOP (12 mm x 20 mm)
- 5V  $\pm$  10% Power Supply
- High-reliability CMOS Technology – 2,000V ESD Protection
  - 200 mA Latch-up Immunity
- Rapid<sup>™</sup> Programming Algorithm 50 µs/Word (Typical)
- CMOS- and TTL-compatible Inputs and Outputs
- Integrated Product Identification Code
- Commercial and Industrial Temperature Ranges

# Description

The AT27C400 is a low-power, high-performance, 4,194,304-bit, one-time programmable read-only memory (OTP EPROM) organized as either 256K by 16 or 512K by 8 bits. It requires a single 5V power supply in normal read mode operation. Any word can be accessed in less than 90 ns, eliminating the need for speed-reducing WAIT states. The by-16 organization makes this part ideal for high-performance 16- and 32bit microprocessor systems. *(continued)* 

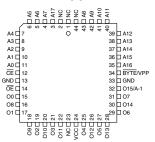
# **Pin Configurations**

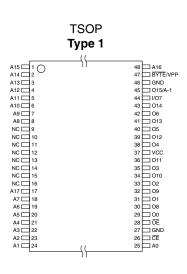
Pin Name	Function
A0 - A17	Addresses
O0 - O15	Outputs
O15/A-1	Output/Address
BYTE/VPP	Byte Mode/ Program Supply
CE	Chip Enable
ŌĒ	Output Enable
NC	No Connect

Note: Both GND pins must be connected. PDIP Top View SOIC (SOP)

וט־		op v	lew	3		50	JF)
- 1		<u> </u>					1
A17 🗆	1	40	A8	NC 🖂	1	44	
A7 🗆	2	39	A9	NC 🖂	2	43	D NC
A6 🗆	3	38	🗆 A10	A17 🗀	3	42	A8
A5 🗆	4	37	A11	A7 🗖	4	41	🗖 A9
A4 🗆	5	36	A12	A6 🗔	5	40	A10
A3 🗆	6	35	🗆 A13	A5 🗖	6	39	A11
A2 🗆	7	34	A14	A4 🗔	7	38	A12
A1 🗆		33	🗆 A15	A3 🗔	8	37	🗖 A13
A0 🗆	9	32	A16	A2 🗀	9	36	🗖 A14
CE	10	31	BYTE/VPP	A1 🗖	10	35	A15
GND 🗖	11	30	GND	A0 🗖	11	34	A16
OE D	12	29	015/A-1	CE 🖂	12	33	BYTE/VPP
00 🗆		28	07	GND 🖂	13	32	GND GND
08 🗆	14	27	014	OE 🖂	14	31	015/A-1
01 🗆	15	26	06	00	15	30	07
O9 🗆		25	013	08 🖂	16	29	014
02 🗆	17	24	05	01 🗆	17	28	06
010		23	012	09 🗀	18	27	013
03 🗆			04	02 🗖	19	26	05
011	20	21	□ vcc	010	20	25	012
				03 🖂	21	24	04
				011	22	23	L vcc
							1

PLCC







4-megabit (256K x 16 or 512K x 8) OTP EPROM

# AT27C400

#### Not Recommended for New Designs

Rev. 0844C-05/00





The AT27C400 can be organized as either word-wide or byte-wide. The organization is selected via the  $\overline{BYTE}/V_{PP}$  pin. When  $\overline{BYTE}/V_{PP}$  is asserted high (V<sub>IH</sub>), the word-wide organization is selected and the O15/A-1 pin is used for O15 data output. When  $\overline{BYTE}/V_{PP}$  is asserted low (V<sub>IL</sub>), the byte-wide organization is selected and the O15/A-1 pin is used for the address pin A-1. When the AT27C400 is logically regarded as x16 (word-wide), but read in the byte-wide mode, then with A-1 = V<sub>IL</sub>, the lower eight bits of the 16-bit word are selected.

In read mode, the AT27C400 typically consumes 15 mA. Standby mode supply current is typically less than 10  $\mu$ A.

The AT27C400 is available in industry-standard, JEDECapproved, one-time programmable (OTP) PDIP, SOIC (SOP) and TSOP packages. The device features two-line control ( $\overline{CE}$ ,  $\overline{OE}$ ) to eliminate bus contention in high-speed systems.

With high-density 256K word or 512K byte storage capability, the AT27C400 allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

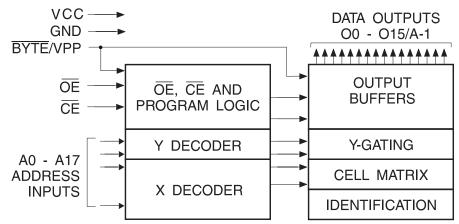
Atmel's AT27C400 has additional features that ensure high quality and efficient production use. The Rapid<sup>™</sup>

Programming Algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 50  $\mu$ s/word. The Integrated Product Identification Code electronically identifies the device and manufacturer. This feature is used by industrystandard programming equipment to select the proper programming algorithms and voltages.

### **System Considerations**

Switching between active and standby conditions via the Chip Enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device non-conformance. At a minimum, a 0.1  $\mu$ F high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and Ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a 4.7  $\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and Ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

### **Block Diagram**





# **Absolute Maximum Ratings\***

Temperature under Bias55°C to +125°C	*NOTICE:	S <sup>.</sup> m
Storage Temperature65°C to +150°C		de
Voltage on Any Pin with Respect to Ground2.0V to +7.0V <sup>(1)</sup>		oj tic tic al
Voltage on A9 with Respect to Ground2.0V to +14.0V <sup>(1)</sup>		pe
$V_{\text{PP}}$ Supply Voltage with Respect to Ground2.0V to +14.0V $^{(1)}$		
Integrated UV Erase Dose		

ICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Note: 1. Minimum voltage is -0.6V DC, which undershoots to -2.0V for pulses of less than 20 ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20 ns.

<b>Operating Modes</b>	
------------------------	--

						Outputs	
Mode/Pin	CE	ŌĒ	Ai	BYTE/V <sub>PP</sub>	0 <sub>0</sub> - 0 <sub>7</sub>	O <sub>8</sub> - O <sub>14</sub>	O <sub>15</sub> /A-1
Read Word-wide	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	V <sub>IH</sub>	D <sub>OUT</sub>	D <sub>OUT</sub>	D <sub>OUT</sub>
Read Byte-wide Upper	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	V <sub>IL</sub>	D <sub>OUT</sub>	High-Z	V <sub>IH</sub>
Read Byte-wide Lower	V <sub>IL</sub>	V <sub>IL</sub>	X <sup>(1)</sup>	V <sub>IL</sub>	D <sub>OUT</sub>	High-Z	V <sub>IL</sub>
Output Disable	X <sup>(1)</sup>	V <sub>IH</sub>	X <sup>(1)</sup>	Х		High-Z	
Standby	V <sub>IH</sub>	X <sup>(1)</sup>	X <sup>(1)</sup>	X <sup>(5)</sup>		High-Z	
Rapid Program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>IH</sub>	Ai	V <sub>PP</sub>		D <sub>IN</sub>	
PGM Verify	Х	V <sub>IL</sub>	Ai	V <sub>PP</sub>		D <sub>OUT</sub>	
PGM Inhibit	V <sub>IH</sub>	V <sub>IH</sub>	X <sup>(1)</sup>	V <sub>PP</sub>		High-Z	
Product Identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A17 = V_{IL}$	V <sub>IH</sub>		Identification Code	

Notes: 1. X can be  $V_{IL}$  or  $V_{IH}$ .

2. Refer to the programming characteristics tables in this datasheet.

3.  $V_{\rm H} = 12.0 \pm 0.5 V$ .

Two identifier words may be selected. All inputs are held low (V<sub>IL</sub>), except A9, which is set to V<sub>H</sub>, and A0, which is toggled low (V<sub>IL</sub>) to select the Manufacturer's Identification word and high (V<sub>IH</sub>) to select the Device Code word.

5. Standby  $V_{CC}$  current (ISB) is specified with  $V_{PP} = V_{CC}$ .  $V_{CC} > V_{PP}$  will cause a slight increase in ISB.





# DC and AC Operating Conditions for Read Operation

		AT27C400					
		-90	-12	-15			
Operating Temperature (Case)	Com.	0°C - 70°C	0°C - 70°C	0°C - 70°C			
	Ind.	-40°C - 85°C	-40°C - 85°C	-40°C - 85°C			
V <sub>CC</sub> Power Supply		$5V\pm10\%$	5V ± 10%	5V ± 10%			

# DC and Operating Characteristics for Read Operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input Load Current	$V_{IN} = 0V$ to $V_{CC}$		±1	μA
I <sub>LO</sub>	Output Leakage Current	$V_{OUT} = 0V$ to $V_{CC}$		±5	μA
I <sub>PP1</sub> <sup>(2)</sup>	V <sub>PP</sub> <sup>(1)</sup> Read/Standby Current	V <sub>PP</sub> = V <sub>CC</sub>		10	μA
		$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μA
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> Standby Current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC}$ + 0.5V		1	mA
	V <sub>CC</sub> Active Current	$f = 5 \text{ MHz}, I_{OUT} = 0 \text{ mA}, \overline{CE} = V_{IL}$		40	mA
V <sub>IL</sub>	Input Low Voltage		-0.6	0.8	V
V <sub>IH</sub>	Input High Voltage		2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$ , and removed simultaneously or after  $V_{PP}$ .

2.  $V_{PP}$  may be connected directly to  $V_{CC}$ , except during programming. The supply current would then be the sum of  $I_{CC}$  and  $I_{PP}$ .

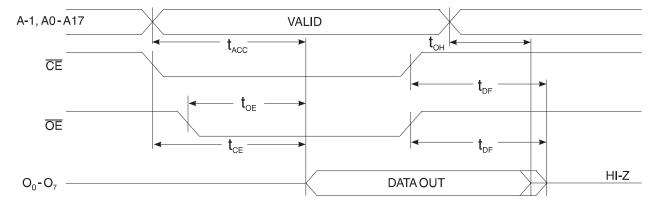
# **AC Characteristics for Read Operation**

			AT27C400						
			-	-90		12	-15		
Symbol	Parameter	Condition	Min	Мах	Min	Max	Min	Мах	Units
t <sub>ACC</sub> <sup>(2)</sup>	Address to Output Delay	$\overline{CE} = \overline{OE} \\ = V_{IL}$		90		120		150	ns
t <sub>CE</sub> <sup>(2)</sup>	CE to Output Delay	$\overline{OE} = V_{IL}$		90		120		150	ns
t <sub>OE</sub> <sup>(2)(3)</sup>	OE to Output Delay	$\overline{CE} = V_{IL}$		35		40		50	ns
t <sub>DF</sub> <sup>(4)(5)</sup>	OE or CE High to Output Float, whichever occurred first			20		30		35	ns
t <sub>OH</sub> <sup>(4)</sup>	Output Hold from Address, CE or OE, whichever occurred first		5		5		5		ns
t <sub>ST</sub>	BYTE High to Output Valid			90		120		150	ns
t <sub>STD</sub>	BYTE Low to Output Transition			40		50		60	ns

Note: 2, 3, 4, 5. See the AC Waveforms for Read Operation diagram.

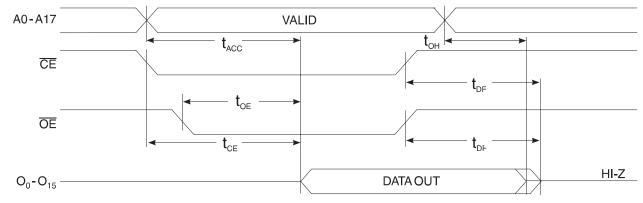
# AT27C400

### Byte-wide Read Mode AC Waveforms



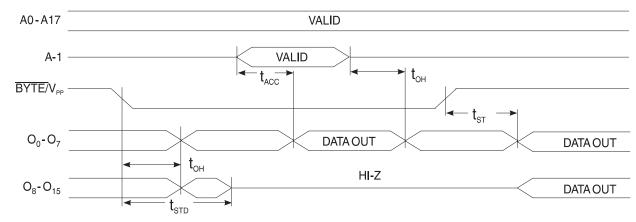
Note:  $\overline{\text{BYTE}}/V_{\text{PP}} = V_{\text{IL}}$ 

### Word-wide Read Mode AC Waveforms



Note:  $\overline{\text{BYTE}}/V_{\text{PP}} = V_{\text{IH}}$ 

# **BYTE** Transition AC Waveforms



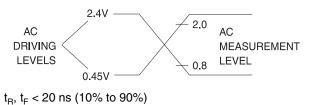
Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

- 2.  $\overline{OE}$  maybe delayed up to t<sub>CE</sub> t<sub>OE</sub> after the falling edge of  $\overline{CE}$  without impact on t<sub>CE</sub>.
- 3.  $\overline{OE}$  maybe delayed up to  $t_{ACC}$   $t_{OE}$  after the address is valid without impact on  $t_{ACC}$ .
- 4. This parameter is only sampled and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

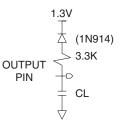




# Input Test Waveforms and Measurement Levels



### **Output Test Load**



Note:  $C_L = 100 \text{ pF}$  including jig capacitance.

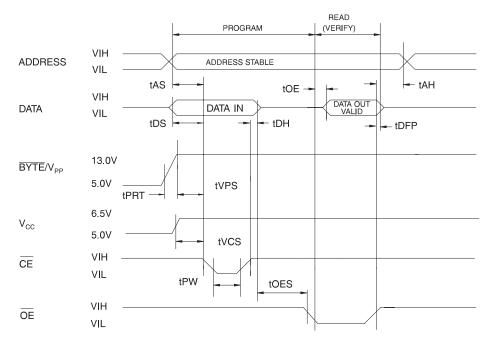
# **Pin Capacitance**

 $f = 1 \text{ MHz}, T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Мах	Max Units	
C <sub>IN</sub>	4	10	pF	$V_{IN} = 0V$
C <sub>OUT</sub>	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

# **Programming Waveforms**<sup>(1)</sup>



- Notes: 1. The Input Timing Reference is 0.8V for  $V_{\rm IL}$  and 2.0V for  $V_{\rm IH}.$ 
  - 2.  $t_{OE}$  and  $t_{DFP}$  are characteristics of the device but mist be accommodated by the programmer.
  - 3. When programming the AT27C400, a 0.1  $\mu$ F capacitor is required across V<sub>PP</sub> and ground to suppress spurious voltage transients.

### **DC Programming Characteristics**

 ${\sf TA} = 25 \pm 5^{\circ}{\sf C}, \, {\sf V}_{\sf CC} = 6.5 \pm 0.25{\sf V}, \, {\sf V}_{\sf PP} = \underline{13.0 \pm 0.25{\sf V}}$ 

			Li	Limits		
Symbol	Parameter	Test Conditions	Min	Max	Units	
ILI	Input Load Current	$V_{IN} = V_{IL}, V_{IH}$		±10	μA	
V <sub>IL</sub>	Input Low Level		-0.6	0.8	V	
V <sub>IH</sub>	Input High Level		2.0	V <sub>CC</sub> + 0.5	V	
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.1 mA		0.4	V	
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -400 μA	2.4		V	
I <sub>CC2</sub>	V <sub>CC</sub> Supply Current (Program and Verify)			50	mA	
I <sub>PP2</sub>	V <sub>PP</sub> Supply Current	$\overline{CE} = V_{IL}$		30	mA	
V <sub>ID</sub>	A9 Product Identification Voltage		11.5	12.5	V	





# **AC Programming Characteristics**

 $TA = 25 \pm 5^{\circ}C, \, V_{CC} = 6.5 \pm 0.25V, \, V_{PP} = 13.0 \pm 0.25V$ 

			Lir	Units	
Symbol	Parameter	Test Conditions <sup>(1)</sup>	Min Max		
t <sub>AS</sub>	Address Setup Time		2		μs
t <sub>OES</sub>	OE Setup Time	Input Diss and Fall Times	2		μs
t <sub>DS</sub>	Data Setup Time	Input Rise and Fall Times: (10% to 90%) 20 ns	2		μs
t <sub>AH</sub>	Address Hold Time		0		μs
t <sub>DH</sub>	Data Hold Time	Input Pulse Levels:	2		μs
t <sub>DFP</sub>	OE High to Output Float Delay <sup>(2)</sup>	0.45V to 2.4V	0	130	ns
t <sub>VPS</sub>	V <sub>PP</sub> Setup Time	Input Timing Reference Level:	2		μs
t <sub>vcs</sub>	V <sub>CC</sub> Setup Time	0.8V to 2.0V	2		μs
t <sub>PW</sub>	CE Program Pulse Width <sup>(3)</sup>	Output Timing Reference Level:	47.5	52.5	μs
t <sub>OE</sub>	Data Valid from $\overline{OE}$	0.8V to 2.0V		150	ns
t <sub>PRT</sub>	BYTE/V <sub>PP</sub> Pulse Rise Time During Programming		50		ns

Notes: 1.  $V_{CC}$  must be applied simultaneously or before  $V_{PP}$  and removed simultaneously or after  $V_{PP}$ .

This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven

 see timing diagram.

3. Program Pulse width tolerance is 50  $\mu\text{sec}\pm5\%.$ 

# Atmel's 27C400 Integrated Product Identification Code

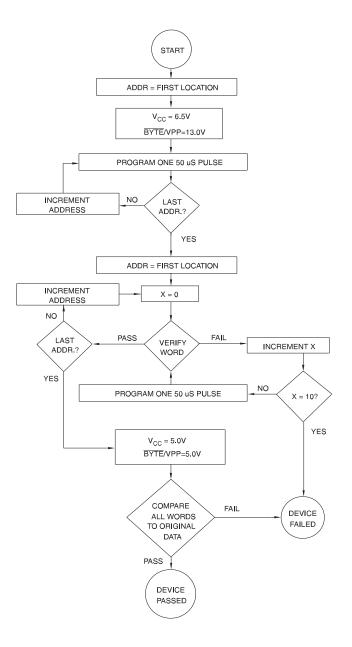
Pins										
	A0	015	014	013	012	011	O10	<b>O</b> 9	08	Hex
Codes		07	06	O5	04	O3	02	01	00	Data
Manufacturer	0	0	0	0	1	1	1	1	0	1E1E
Device Type	1	1	1	1	1	0	1	0	0	F4F4

AT27C400

## **Rapid Programming Algorithm**

A 50  $\mu$ s  $\overline{CE}$  pulse width is used to program. The address is set to the first location. V<sub>CC</sub> is raised to 6.5V and  $\overline{BYTE}/V_{PP}$  is raised to 13.0V. Each address is first programmed with one 50  $\mu$ s  $\overline{CE}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a word fails to pass verification, up to 10 successive 50  $\mu$ s pulses are applied with a verification after each

pulse. If the word fails to verify after 10 pulses have been applied, the part is considered failed. After the word verifies properly, the next address is selected until all have been checked.  $V_{PP}$  is then lowered to 5.0V and  $V_{CC}$  to 5.0V. All words are read again and compared with the original data to determine if the device passes or fails.





# **Ordering Information**

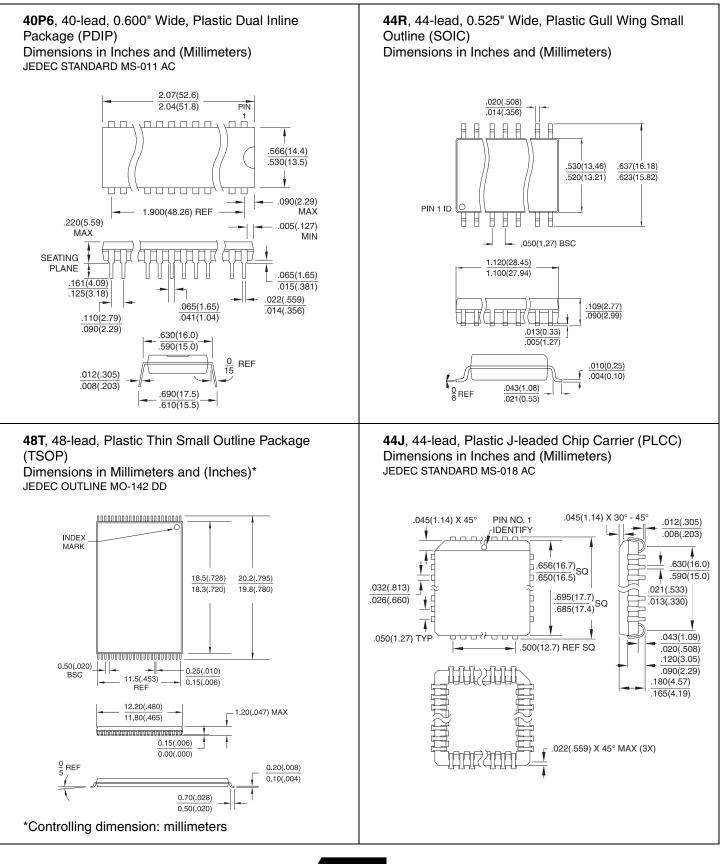
t <sub>ACC</sub> (ns)	I <sub>CC</sub> (mA)				
	Active	Standby	Ordering Code	Package	<b>Operation Range</b>
90	40	0.1	AT27C400-90PC	40P6	Commercial
			AT27C400-90RC	44R	(0°C to 70°C)
			AT27C400-90TC	48T	
			AT27C400-90JC	44J	
	40	0.1	AT27C400-90PI	40P6	Industrial
			AT27C400-90RI	44R	(-40°C to 85°C)
			AT27C400-90TI	48T	
			AT27C400-90JI	44J	
120	40	0.1	AT27C400-12PC	40P6	Commercial
			AT27C400-12RC	44R	(0°C to 70°C)
			AT27C400-12TC	48T	
			AT27C400-12JC	44J	
	40	0.1	AT27C400-12PI	40P6	Industrial
			AT27C400-12RI	44R	(-40°C to 85°C)
			AT27C400-12TI	48T	
			AT27C400-12JI	44J	
150	40	0.1	AT27C400-15PC	40P6	Commercial
			AT27C400-15RC	44R	(0°C to 70°C)
			AT27C400-15TC	48T	
			AT27C400-15JC	44J	
	40	0.1	AT27C400-15PI	40P6	Industrial
			AT27C400-15RI	44R	(-40°C to 85°C)
			AT27C400-15TI	48T	
			AT27C400-15JI	44J	

Package Type					
40-lead, 0.600" Wide, Plastic Dual Inline Package (PDIP)					
44-lead, 0.525" Wide, Plastic Gull Wing Small Outline Package (SOIC/SOP)					
48-lead, Plastic Thin Small Outline Package (TSOP) 12 x 20 mm					
44-lead, Plastic J-leaded Chip Carrier (PLCC)					
-					

# AT27C400

AT27C400

### **Packaging Information**



11



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